

ABIST-ASSISTED DETECTION OF SCAN CHAIN DEFECTS

Abstract of the Disclosure

5 An apparatus, program product and method utilize an ABIST circuit provided on an integrated circuit device to assist in the identification and location of defects in a scan chain that is also provided on the integrated circuit device. In particular, a defect in a scan chain may be detected by applying a plurality of pattern sets to a scan chain coupled to an ABIST circuit, collecting scan out data generated as a result of the application of the plurality of pattern sets to the scan chain, and using the collected scan out data to identify a defective latch in the scan chain.